### Fabricating Microgeometry for Custom Surface Reflectance

SIGGRAPH 2009 August 4, New Orleans

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## Acquiring & Fabricating Geometry



Wikimedia Common

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- Net effect described by *microfacet distribution* (MFD)



1-D Microfacet Distribution



Appearance

Reflectance as a result of microgeometry

- Surface modelled by tiny mirrors (*microfacets*)
   [TORRANCE AND SPARROW 1967]
- Net effect described by microfacet distribution (MFD)
- MFD can be estimated from measured data
   [NGAN ET AL. 2005]



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• Our goal:

fabricating microgeometry from an MFD

#### Material design and editing

- Aggregate BRDF from arbitrary microgeometry or MFD [WESTIN ET A. 1992; ASHIKHMIN ET AL. 2000]



[ASHIKHMIN ET AL. 2000]

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- Reflector design
  - Search for mirror geometry with target radiation [PATOW AND PUEYO 2005; PATOW ET AL. 2007]



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### Reflector design

- Search for mirror geometry with target radiation [PATOW AND PUEYO 2005; PATOW ET AL. 2007]
- But fixed light source position and not planar



- Physical appearance output
  - 3-D printing of artistic geometry [SÉQUIN 2000]



Séquin 2005

#### Physical appearance output

- 3-D printing of artistic geometry [SÉQUIN 2000]
- Bas-relief sculpture outputs macroscopic appearance
  [CIGNONI ET AL. 1997; WEYRICH ET AL. 2007; SONG ET AL. 2007; KERBER ET AL. 2007]





#### Physical appearance output

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- Bas-relief sculpture outputs macroscopic appearance
   [CIGNONI ET AL. 1997; WEYRICH ET AL. 2007; SONG ET AL. 2007; KERBER ET AL. 2007]
- But no user-defined reflectance output





[WEYRICH ET AL. 2007]

### **Problem Definition**

- BRDF specification by microfacet distribution (MFD)
- Find microgeometry that
  - has normals that satisfy MFD
  - is a height field
  - is tileable (for efficiency)

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- In a sense, MFD integration problem
- Related to Poisson problem
  - except that gradient *locations* not known

# Approach

#### Desired Highlight Shape (MFG)







## Approach





### **Reflectance Specification**

#### Target BRDF assumptions

- Spatially homogeneous
- Purely specular (describable by MFD)

#### Hemispherical MFD

- Defined by highlight under frontal illumination
- 2-D representation in parabolic mapping



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Goal:

Shaping base material to exhibit aggregate target BRDF

### Accounting For Base BRDF

Deconvolving Target MFD by Base BRDF
 Lucy-Richardson deconvolution algorithm



Target MFD

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Deconvolving Target MFD by Base BRDF
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Base MFD

Target MFD

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Target MFD

Deconvolved by base MFD
# Accounting For Base BRDF



Microfacets cannot control "brightness" of a reflection



Microfacets cannot control "brightness" of a reflection
"Stippling" instead: drawing discrete facets from MFD



#### Low-discrepancy sampling required



Target MFD



Random Sampling

- Low-discrepancy sampling required
- We use centroidal Voronoi tesselation [SECORD 2002]









Low-discrepancy Sampling

Target MFD

# Result of MF Sampling



## Result of MF Sampling

> Should exhibit desired aggregate reflectance...



# Result of MF Sampling

- Should exhibit desired aggregate reflectance...
- ... but:
  - Discontinuities hard to manufacture
  - Interreflection at verticals

## Height Field Optimization

Maximize continuity and integrability



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- Two-stage procedure
  - 1. Arrangement

## Height Field Optimization

- Maximize continuity and integrability
- Two-stage procedure
  - 1. Arrangement
  - 2. Vertical displacement

Shuffling facets to optimize:



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 Compatibility of neighboring slopes





- Shuffling facets to optimize:
  - Compatibility of neighboring slopes
  - Mean-free rows and columns





#### Shuffling facets to optimize:

- Compatibility of neighboring slopes
- Mean-free rows and columns
- Minimize "valleys" in end result
  - (physical process causes horizontal flats at concavities)

Shuffling

#### Shuffle using simulated annealing optimization



#### Shuffle using simulated annealing optimization

- Global penalty function
- Pair-wise facet swaps
- Logarithmic annealing schedule





### **Displacement** Optimization

#### Vertical displacement to minimize discontinuities



### **Displacement** Optimization

- Vertical displacement to minimize discontinuities
- Maps to Poisson problem
  - Facets determine local gradients
  - Cyclic connectivity for tileability



## Displacement Optimization



## Effect of Valley Optimization

- Halves horizontal areas
- Preserves continuity



418 Concave Edges

### Fabricating Microgeometry

Requires shaping glossy materials



## Fabricating Microgeometry

- Requires shaping glossy materials
- Many processes exist
  - Milling
  - Etching
  - Cutting
  - Minting



Prototype fabrication
 Base material: aluminum
 Computer-controlled mill



- Prototype fabrication
  - Base material: aluminum
  - Computer-controlled mill
- Practical challenges
  - Drill bit tip has finite extent
  - Milling creates grooves
  - Milling speed



- Process Details
  - Milling at 0.001-inch resolution
  - Milling x- and y-scanlines

#### Process Details

- Milling at 0.001-inch resolution
- Milling x- and y-scanlines
- Sample size
  - 30×30-height field
  - ca. 1mm<sup>2</sup> facets
  - Overall milling time: 5.5 hours







# Highlight Observation

- Distant light source + distant observer
  - Mirror reflection where facet orientations match
  - No visible highlight



## Highlight Observation

- Distant light source + local observer
  - Multiple off-specular observations
  - Visible highlight formation



## Highlight Observation

#### Distant light source + local observer

- Multiple off-specular observations
- Visible highlight formation
- Requires tiled material



Imaging reflectance lobe

- Imaging reflectance lobe
- Experimental setup:



- Imaging reflectance lobe
- Experimental setup:



- Imaging reflectance lobe
- Experimental setup:



### Results










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5







5











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# **Curved Surfaces**

Curved surface + general observer

- Multiple off-specular observations
- Visible highlight formation



Observer

# Curved Surfaces

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(Simulation)

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Curved surface + general observer

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- Visible highlight formation





(Simulation)

Only integrable MFDs

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  - Barycenter along surface normal

## Only integrable MFDs

- Barycenter along surface normal
- "What goes up has to go down"



# Only integrable MFDs

- Barycenter along surface normal
- "What goes up has to go down"
- Purely specular reflectance



# Only integrable MFDs Barycenter along surface normal "What goes up has to go down" Purely specular reflectance Shadowing term implicit



## Various application scenarios exist

Architectural decorations



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- Material design (not selection)



Courtesy by Vicky Shaw

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- Lighting control (interior design)



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- Logos, product design, etc.



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Manufacturing methods are application-dependent

Microgeometry computation remains general



# Acknowledgments

- Saskia Mardijck, Bruce Lamond, Monica Nichelson, Paul Debevec, Bill Swartout, Randy Hill, Randolph Hall
- NSF grants CCF-0347427 and CCF-0702580
- U.S. Army Research, Development, and Engineering Command (RDECOM)
- University of Southern California Office of the Provost

The content of the information does not necessarily reflect the position or the policy of the US Government, and no official endorsement should be inferred.